

#### **DATASHEET**

## **Description**

The 9DML04 devices are 3.3V members of IDT's Full-Featured PCIe family. The 9DML04 supports PCIe Gen1-4 Common Clocked (CC), Separate Reference no Spread (SRnS), and Separate Reference Independent Spread (SRIS) architectures. The part provides a choice of asynchronous and glitch-free switching modes, and offers a choice of integrated output terminations providing direct connection to  $85\Omega$  or  $100\Omega$  transmission lines. The 9DML04P1 can be factory programmed with a user-defined power up default SMBus configuration.

#### **Recommended Application**

Servers, ATCA, ATE, Master/Slave applications

#### **Output Features**

- 4 1~200 MHz Low-Power HCSL (LP-HCSL) DIF pairs
  - 9DML0441 default Zout =  $100\Omega$
  - 9DML0451 default Zout =  $85\Omega$
  - 9DML04P1 factory programmable defaults

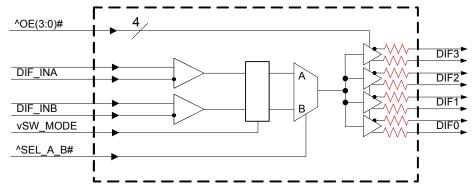
#### **Key Specifications**

- PCIe Gen1-2-3-4 CC compliant
- PCIe Gen2-3 SRIS compliant
- DIF additive cycle-to-cycle jitter <1ps
- DIF output-to-output skew <50ps
- Additive phase jitter is <0.1ps rms for PCIe</li>
- Additive phase jitter 160fs rms typ. @156.25M (1.5M to 10M)

#### Features/Benefits

- Direct connection to  $100\Omega$  (xx41) or  $85\Omega$  (xx51) transmission lines; saves 16 resistors compared to standard PCIe devices
- 76mW typical power consumption; eliminates thermal concerns
- Spread Spectrum (SS) compatible; allows SS for EMI reduction
- Customer defined power up default can be factory programmed into P1 device; allows exact optimization to customer requirements:
  - · control input polarity
  - control input pull up/downs
  - · slew rate for each output
  - · differential output amplitude
  - · output impedance for each output
- OE# pins; support DIF power management
- HCSL-compatible differential inputs; can be driven by common clock source
- Selectable asynchronous or glitch-free switching; allows the mux to be selected at power up even if both inputs are not running, then transition to glitch-free switching mode
- Space saving 24-pin 4x4mm VFQFPN; minimal board space

## **Block Diagram**

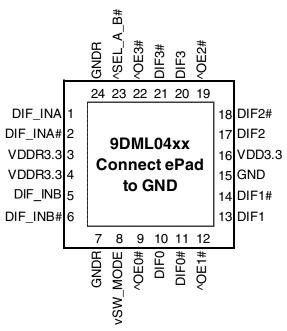


1

Note: Resistors default to internal on 41/51 devices. P1 devices have programmable default impedances on an output-by-output basis.



## **Pin Configuration**



#### 24 VFQFPN, 4x4 mm, 0.5mm pitch

^ prefix indicates internal 120KOhm pull up resistor v prefix indicates internal 120KOhm pull down resistor

#### **Power Management Table**

OEx# Pin	DIF IN	DIFx				
OLX# FIII	Dir_iii	True O/P	Comp. O/P			
0	Running	Running	Running			
1	Running	Low	Low			

#### **Power Connections**

Pin N	umber	Description				
VDD	GND	Description				
3	24	Input A receiver analog				
4	7	Input B receiver analog				
16	15	DIF outputs				

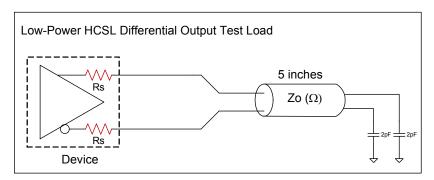


## **Pin Descriptions**

Pin#	Pin Name	Type	Pin Description
1	DIF_INA	IN	HCSL Differential True input
2	DIF_INA#	IN	HCSL Differential Complement Input
3	VDDR3.3	PWR	3.3V power for differential input clock (receiver). This VDD should be treated
3	VDD110.0	FVVII	as an Analog power rail and filtered appropriately.
4	VDDR3.3	PWR	3.3V power for differential input clock (receiver). This VDD should be treated
-		I VVII	as an Analog power rail and filtered appropriately.
5	DIF_INB	IN	HCSL Differential True input
6	DIF_INB#	IN	HCSL Differential Complement Input
7	GNDR	GND	Analog Ground pin for the differential input (receiver)
			Switch Mode. This pin selects either asynchronous or glitch-free switching of
			the mux. Use asynchronous mode if 0 or 1 of the input clocks is running.
8	vSW_MODE	IN	Use glitch-free mode if both input clocks are running. This pin has an internal
"	V3VV_IVIODE	IIN	pull down resistor of ~120kohms.
			0 = asynchronous mode
			1 = glitch-free mode
			Active low input for enabling DIF pair 0. This pin has an internal pull-up
9	^OE0#	IN	resistor.
			1 =disable outputs, 0 = enable outputs
10	DIF0	OUT	Differential true clock output
11	DIF0#	OUT	Differential Complementary clock output
			Active low input for enabling DIF pair 1. This pin has an internal pull-up
12	^OE1#	IN	resistor.
			1 =disable outputs, 0 = enable outputs
13	DIF1	OUT	Differential true clock output
14	DIF1#	OUT	Differential Complementary clock output
15	GND	GND	Ground pin.
16	VDD3.3	PWR	Power supply, nominal 3.3V
17	DIF2	OUT	Differential true clock output
18	DIF2#	OUT	Differential Complementary clock output
			Active low input for enabling DIF pair 2. This pin has an internal pull-up
19	^OE2#	IN	resistor.
			1 =disable outputs, 0 = enable outputs
20	DIF3	OUT	Differential true clock output
21	DIF3#	OUT	Differential Complementary clock output
			Active low input for enabling DIF pair 3. This pin has an internal pull-up
22	^OE3#	IN	resistor.
			1 =disable outputs, 0 = enable outputs
			Input to select differential input clock A or differential input clock B. This
23	^SEL_A_B#	IN	input has an internal pull-up resistor.
			0 = Input B selected, 1 = Input A selected.
24	GNDR	GND	Analog Ground pin for the differential input (receiver)
25	EPAD	GND	Connect to Ground.



### **Test Loads**



#### **Terminations**

Ζο (Ω)	Rs (Ω)
100	None needed
100	7.5
100	Prog.
85	N/A
85	None needed
85	Prog.
	100 100 100 85 85

#### **Alternate Terminations**

The 9DML family can easily drive LVPECL, LVDS, and CML logic. See <u>"AN-891 Driving LVPECL, LVDS, and CML Logic with IDT's "Universal" Low-Power HCSL Outputs"</u> for details.



#### **Absolute Maximum Ratings**

Stresses above the ratings listed below can cause permanent damage to the 9DML04. These ratings, which are standard values for IDT commercially rated parts, are stress ratings only. Functional operation of the device at these or any other conditions above those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods can affect product reliability. Electrical parameters are guaranteed only over the recommended operating temperature range.

PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNITS	NOTES
Supply Voltage	VDDx				4.6	V	1,2
Input Voltage	$V_{IN}$		-0.5		V <sub>DD</sub> +0.5	V	1,3
Input High Voltage, SMBus	$V_{IHSMB}$	SMBus clock and data pins			3.9	V	1
Storage Temperature	Ts		-65		150	ô	1
Junction Temperature	Tj			·	125	ô	1
Input ESD protection	ESD prot	Human Body Model	2500			٧	1

<sup>&</sup>lt;sup>1</sup>Guaranteed by design and characterization, not 100% tested in production.

### **Electrical Characteristics-Clock Input Parameters**

TA = T<sub>AMB</sub> Supply Voltages per normal operation conditions, See Test Loads for Loading Conditions

The Talib, Supply Voltages for Hermal operation contained, See Test Education Education										
PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNITS	NOTES			
Input Common Mode Voltage - DIF_IN	V <sub>COM</sub>	Common Mode Input Voltage	150		900	mV	1			
Input Swing - DIF_IN	V <sub>SWING</sub>	Differential value	300			mV	1			
Input Slew Rate - DIF_IN	dv/dt	Measured differentially	0.4		8	V/ns	1,2			
Input Leakage Current	I <sub>IN</sub>	$V_{IN} = V_{DD}$ , $V_{IN} = GND$	-5		5	uA				
Input Duty Cycle	d <sub>tin</sub>	Measurement from differential wavefrom	45		55	%	1			
Input Jitter - Cycle to Cycle	$J_{DIFIn}$	Differential Measurement	0		125	ps	1			

<sup>&</sup>lt;sup>1</sup> Guaranteed by design and characterization, not 100% tested in production.

## **Electrical Characteristics-Current Consumption**

TA = T<sub>AMB.</sub> Supply Voltages per normal operation conditions, See Test Loads for Loading Conditions

PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNITS	NOTES
Operating Supply Current	I <sub>DD</sub>	VDD, All outputs active @100MHz		23	30	mA	
Powerdown Current	I <sub>DDPD</sub>	VDD, all outputs disabled		1.6	2.5	mA	1

<sup>&</sup>lt;sup>1</sup> Input clock stopped.

<sup>&</sup>lt;sup>2</sup> Operation under these conditions is neither implied nor guaranteed.

<sup>&</sup>lt;sup>3</sup> Not to exceed 4.6V.

<sup>&</sup>lt;sup>2</sup>Slew rate measured through +/-75mV window centered around differential zero



# **Electrical Characteristics-Input/Supply/Common Parameters-Normal Operating Conditions**

TA = T<sub>AMB</sub>, Supply Voltages per normal operation conditions, See Test Loads for Loading Conditions

AIVID,   -   -   -   -   -   -   -   -		7					
PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNITS	NOTES
Supply Voltage	VDDx	Supply voltage for core and analog	3.135	3.3	3.465	V	
Ambient Operating Temperature	T <sub>AMB</sub>	Industrial range	-40	25	85	°C	
Input High Voltage	V <sub>IH</sub>	Single-ended inputs, except SMBus	0.75 V <sub>DD</sub>		$V_{DD} + 0.3$	V	
Input Low Voltage	V <sub>IL</sub>	Single-ended inputs, except SMBus	-0.3		0.25 V <sub>DD</sub>	V	
	I <sub>IN</sub>	Single-ended inputs, $V_{IN} = GND$ , $V_{IN} = VDD$	-5		5	uA	
Input Current	I <sub>INP</sub>	$\label{eq:VIN} Single-ended inputs \\ V_{IN} = 0 \ V; \ Inputs \ with internal pull-up resistors \\ V_{IN} = VDD; \ Inputs \ with internal pull-down resistors$	-50		50	uA	
Input Frequency	F <sub>ibyp</sub>		1		200	MHz	2
Pin Inductance	$L_{pin}$				7	nH	1
	C <sub>IN</sub>	Logic Inputs, except DIF_IN	1.5		5	pF	1
Capacitance	C <sub>INDIF_IN</sub>	DIF_IN differential clock inputs	1.5		2.7	pF	1
	C <sub>OUT</sub>	Output pin capacitance			6	pF	1
Clk Stabilization	T <sub>STAB</sub>	From V <sub>DD</sub> Power-Up and after input clock stabilization or de-assertion of PD# to 1st clock		0.7	1	ms	1,2
Input SS Modulation Frequency PCIe	f <sub>MODINPCle</sub>	Allowable Frequency for PCIe Applications (Triangular Modulation)	30	31.5	33	kHz	
Input SS Modulation Frequency non-PCle	f <sub>MODIN</sub>	Allowable Frequency for non-PCIe Applications (Triangular Modulation)	0		66	kHz	
OE# Latency	t <sub>LATOE#</sub>	DIF start after OE# assertion DIF stop after OE# deassertion	1	2	3	clocks	1,3
Tdrive_PD#	t <sub>DRVPD</sub>	DIF output enable after PD# de-assertion			300	us	1,3
Tfall	t <sub>F</sub>	Fall time of single-ended control inputs			5	ns	2
Trise	t <sub>R</sub>	Rise time of single-ended control inputs	_		5	ns	2

<sup>&</sup>lt;sup>1</sup>Guaranteed by design and characterization, not 100% tested in production.

<sup>&</sup>lt;sup>2</sup>Control input must be monotonic from 20% to 80% of input swing.

<sup>&</sup>lt;sup>3</sup>Time from deassertion until outputs are >200 mV

<sup>&</sup>lt;sup>4</sup>The differential input clock must be running for the SMBus to be active



#### **Electrical Characteristics-DIF Low-Power HCSL Outputs**

TA = T<sub>AMB</sub>. Supply Voltages per normal operation conditions, See Test Loads for Loading Conditions

PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNITS	NOTES
Slew rate	dV/dt	Scope averaging on, default settings	1.5	2.6	4	V/ns	1,2,3
Slew rate matching	∆dV/dt	Slew rate matching		8.6	20	%	1,2,4
Voltage High	V <sub>HIGH</sub>	Statistical measurement on single-ended signal	660	780	850	mV	7
Voltage Low	$V_{LOW}$	using oscilloscope math function. (Scope averaging on)		-32	150	IIIV	7
Max Voltage	Vmax	Measurement on single ended signal using		835	1150	mV	7
Min Voltage	Vmin	absolute value. (Scope averaging off)	-300	-90		IIIV	7
Crossing Voltage (abs)	Vcross_abs	Scope averaging off	250	406	550	mV	1,5
Crossing Voltage (var)	∆-Vcross	Scope averaging off		20	140	mV	1,6

<sup>&</sup>lt;sup>1</sup>Guaranteed by design and characterization, not 100% tested in production.

## Electrical Characteristics-Output Duty Cycle, Jitter, Skew and PLL Characteristics

TA = T<sub>AMB</sub>, Supply Voltages per normal operation conditions, See Test Loads for Loading Conditions

PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	UNITS	NOTES
Duty Cycle Distortion	t <sub>DCD</sub>	Measured differentially, @100MHz	-0.5	0.3	1.2	%	1,3
Skew, Input to Output	t <sub>pd</sub>	V <sub>T</sub> = 50%	2600	3428	4500	ps	1
Skew, Output to Output	t <sub>sk3</sub>	V <sub>T</sub> = 50%		23	50	ps	1
Jitter, Cycle to cycle	t <sub>jcyc-cyc</sub>	Additive Jitter in Bypass Mode		0.1	1	ps	1,2

<sup>&</sup>lt;sup>1</sup> Guaranteed by design and characterization, not 100% tested in production.

<sup>&</sup>lt;sup>2</sup> Measured from differential waveform

<sup>&</sup>lt;sup>3</sup> Slew rate is measured through the Vswing voltage range centered around differential 0V. This results in a +/-150mV window around differential 0V. These are defaults for the 41/51 devices, alternate settings are available in the P1 device.

<sup>&</sup>lt;sup>4</sup> Matching applies to rising edge rate for Clock and falling edge rate for Clock#. It is measured using a +/-75mV window centered on the average cross point where Clock rising meets Clock# falling. The median cross point is used to calculate the voltage thresholds the oscilloscope is to use for the edge rate calculations.

<sup>&</sup>lt;sup>5</sup> Vcross is defined as voltage where Clock = Clock# measured on a component test board and only applies to the differential rising edge (i.e. Clock rising and Clock# falling).

<sup>&</sup>lt;sup>6</sup> The total variation of all Vcross measurements in any particular system. Note that this is a subset of Vcross\_min/max (Vcross absolute) allowed. The intent is to limit Vcross induced modulation by setting Δ-Vcross to be smaller than Vcross absolute.

<sup>&</sup>lt;sup>7</sup> These are defaults for the 41/51 devices. They are factory adjustable in the P1 device.

<sup>&</sup>lt;sup>2</sup> Measured from differential waveform

<sup>&</sup>lt;sup>3</sup> Duty cycle distortion is the difference in duty cycle between the output and the input clock.



## Electrical Characteristics-Filtered Phase Jitter Parameters - PCle Common Clocked (CC) Architectures

T<sub>AMB</sub> = over the specified operating range. Supply Voltages per normal operation conditions, See Test Loads for Loading Conditions

PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	INDUSTRY LIMIT	UNITS	Notes
	t <sub>jphPCleG1-CC</sub>	PCIe Gen 1		0.0	0.01		ps (p-p)	1,2,3,5
Additive Phase Jitter	tjphPCleG2-CC	PCIe Gen 2 Lo Band 10kHz < f < 1.5MHz (PLL BW of 5-16MHz or 8-5MHz, CDR = 5MHz)		0.0	0.01		ps (rms)	1,2,4,5
		PCIe Gen 2 High Band 1.5MHz < f < Nyquist (50MHz) (PLL BW of 5-16MHz or 8-5MHz, CDR = 5MHz)		0.0	0.01	n/a	ps (rms)	1,2,4,5
		PCIe Gen 3 (PLL BW of 2-4MHz or 2-5MHz, CDR = 10MHz)		0.0	0.01		ps (rms)	1,2,4,5
	t <sub>jphPCleG4-CC</sub>	PCIe Gen 4 (PLL BW of 2-4MHz or 2-5MHz, CDR = 10MHz)		0.0	0.01		ps (rms)	1,2,4,5

<sup>&</sup>lt;sup>1</sup> Applies to all outputs.

## Electrical Characteristics-Filtered Phase Jitter Parameters - PCle Separate Reference Independent Spread (SRIS) Architectures<sup>5</sup>

T<sub>AMB</sub> = over the specified operating range. Supply Voltages per normal operation conditions, See Test Loads for Loading Conditions

PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	INDUSTRY LIMIT	UNITS	Notes
	t <sub>jphPCleG2</sub> - SRIS	PCIe Gen 2 (PLL BW of 16MHz , CDR = 5MHz)		0.0	0.01	2/0	ps (rms)	1,2,4
	t <sub>jphPCleG3</sub> -	PCIe Gen 3 (PLL BW of 2-4MHz or 2-5MHz, CDR = 10MHz)		0.0	0.01	n/a	ps (rms)	1,2,4

<sup>&</sup>lt;sup>1</sup> Applies to all outputs.

#### **Electrical Characteristics- Unfiltered Phase Jitter Parameters**

 $TA = T_{AMB}$ , Supply Voltages per normal operation conditions, See Test Loads for Loading Conditions

						INDUSTRY		
PARAMETER	SYMBOL	CONDITIONS	MIN	TYP	MAX	LIMIT	UNITS	Notes
Additive Phase Jitter, Fanout Mode	t <sub>jph156M</sub>	156.25MHz, 1.5MHz to 10MHz, -20dB/decade rollover < 1.5MHz, -40db/decade rolloff > 10MHz		159		N/A	fs (rms)	1,2,3
	t <sub>jph156M12k-</sub> 20	156.25MHz, 12kHz to 20MHz, -20dB/decade rollover <12kHz, -40db/decade rolloff > 20MHz		363		N/A	fs (rms)	1,2,3

<sup>&</sup>lt;sup>1</sup> Guaranteed by design and characterization, not 100% tested in production.

<sup>&</sup>lt;sup>2</sup> Based on PCle Base Specification Rev4.0 version 0.7draft. See http://www.pcisig.com for latest specifications.

<sup>&</sup>lt;sup>3</sup> Sample size of at least 100K cycles. This figures extrapolates to 108ps pk-pk @ 1M cycles for a BER of 1-12.

<sup>&</sup>lt;sup>4</sup> For RMS values additive jitter is calculated by solving the following equation for b  $[a^2+b^2=c^2]$  where a is rms input jitter and c is rms total

<sup>&</sup>lt;sup>5</sup> Driven by 9FGL0841 or equivalent

<sup>&</sup>lt;sup>2</sup> Based on PCIe Base Specification Rev3.1a. These filters are different than Common Clock filters. See http://www.pcisig.com for latest

<sup>&</sup>lt;sup>3</sup> Sample size of at least 100K cycles. This figures extrapolates to 108ps pk-pk @ 1M cycles for a BER of 1-12.

<sup>&</sup>lt;sup>4</sup> For RMS values, additive jitter is calculated by solving the following equation for b [a^2+b^2=c^2] where a is rms input jitter and c is rms total

<sup>&</sup>lt;sup>5</sup> As of PCIe Base Specification Rev4.0 draft 0.7, SRIS is not currently defined for Gen1 or Gen4.

<sup>&</sup>lt;sup>2</sup> Driven by Rohde&Schartz SMA100

<sup>&</sup>lt;sup>3</sup> For RMS figures, additive jitter is calculated by solving the following equation: Additive jitter = SQRT[(total jitter)^2 - (input jitter)^2]



## **Marking Diagrams**







#### Notes:

- 1. "LOT" is the lot sequence number.
- 2. "YYWW" or "YWW" is the digits of the year and week that the part was assembled.
- 3. "I" denotes industrial temperature range device.
- 4. "P" denotes factory programmable defaults. 5. "\*\*" denotes the lot sequence.
- 6. "\$" denotes the mark code.

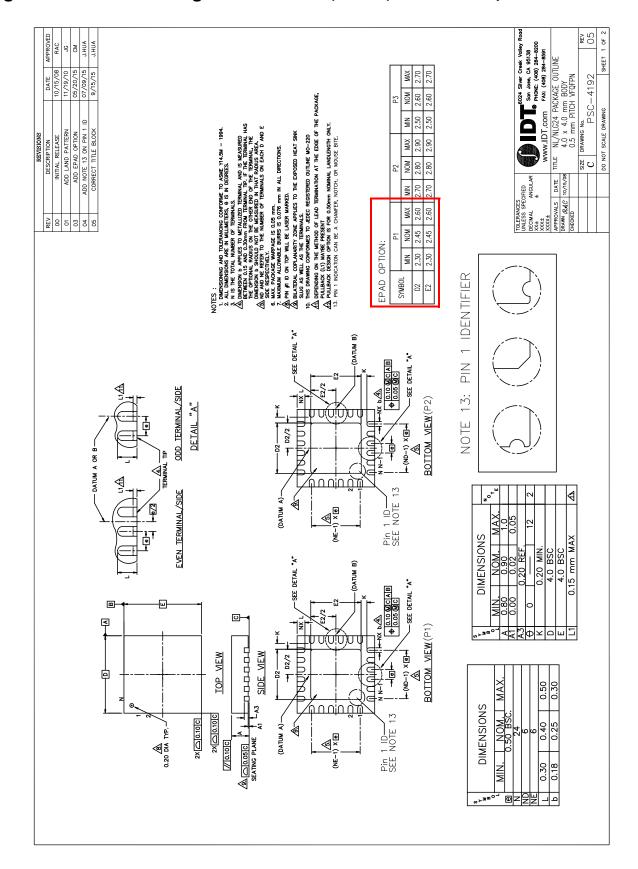
#### **Thermal Characteristics**

PARAMETER	SYMBOL	CONDITIONS	PKG	TYP VALUE	UNITS	NOTES
	θ <sub>JC</sub>	Junction to Case	NLG24	42	°C/W	1
	$\theta_{Jb}$	Junction to Base		2.4	°C/W	1
Thermal Resistance	$\theta_{JA0}$	Junction to Air, still air		39	°C/W	1
Thermal nesistance	$\theta_{JA1}$	Junction to Air, 1 m/s air flow		33	°C/W	1
	θ <sub>ЈАЗ</sub>	Junction to Air, 3 m/s air flow		28	°C/W	1
	$\theta_{JA5}$	Junction to Air, 5 m/s air flow		27	°C/W	1

<sup>&</sup>lt;sup>1</sup>ePad soldered to board

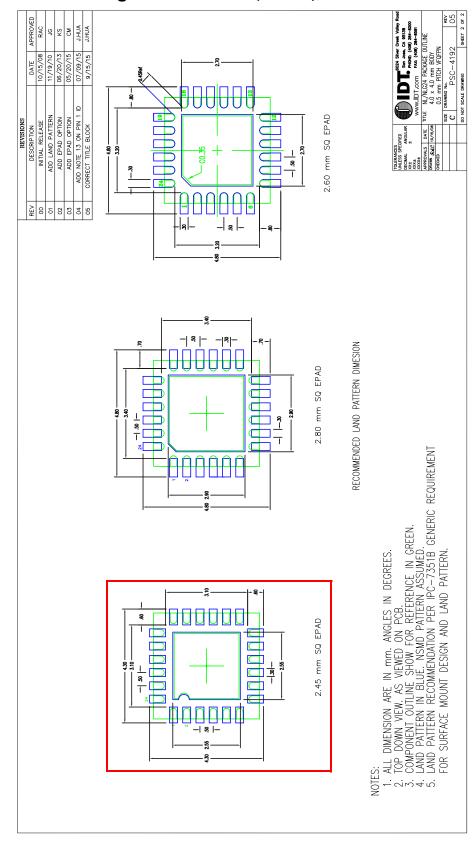


## Package Outline and Package Dimensions (NLG24). Use EPAD Option P1





### Package Outline and Package Dimensions (NLG24), cont. Use 2.45mm SQ EPAD





## **Ordering Information**

Part / Order Number	Notes	ShippingPackaging	Package	Temperature	
9DML0441AKILF	100Ω	Trays	24-pin VFQFPN	-40 to +85° C	
9DML0441AKILFT	10022	Tape and Reel	24-pin VFQFPN	-40 to +85° C	
9DML0451AKILF	85Ω	Trays	24-pin VFQFPN	-40 to +85° C	
9DML0451AKILFT	0012	Tape and Reel	24-pin VFQFPN	-40 to +85° C	
9DML04P1AxxxKILF	Factory configurable.  Contact IDT for	Trays	24-pin VFQFPN	-40 to +85° C	
9DML04P1AxxxKILFT	addtional information.	Tape and Reel	24-pin VFQFPN	-40 to +85° C	

<sup>&</sup>quot;LF" suffix to the part number are the Pb-Free configuration and are RoHS compliant.

## **Revision History**

Rev.	Initiator	Issue Date	Description	Page #
А	RDW	6/6/2016	<ol> <li>Updated leakage current spec for inputs with pull/up/down to +/-50uA.</li> <li>Updated electrical tables with char data</li> <li>Update Front page text</li> <li>Updated ordering information</li> <li>Move to Final.</li> </ol>	Various

<sup>&</sup>quot;A" is the device revision designator (will not correlate with the datasheet revision).

<sup>&</sup>quot;xxx" is a unique factory assigned number to identify a particular default configuration.



Corporate Headquarters 6024 Silver Creek Valley Road San Jose, CA 95138 USA www.IDT.com

Sales

1-800-345-7015 or 408-284-8200 Fax: 408-284-2775

www.IDT.com/go/sales

**Tech Support** 

www.idt.com/go/support

DISCLAIMER Integrated Device Technology, Inc. (IDT) and its subsidiaries reserve the right to modify the products and/or specifications described herein at any time and at IDT's sole discretion. All information in this document, including descriptions of product features and performance, is subject to change without notice. Performance specifications and the operating parameters of the described products are determined in the independent state and are not guaranteed to perform the same way when installed in customer products. The information contained herein is provided without representation or warranty of any kind, whether express or implied, including, but not limited to, the suitability of IDT's products for any particular purpose, an implied warranty of merchantability, or non-infringement of the intellectual property rights of others. This document is presented only as a guide and does not convey any license under intellectual property rights of IDT or any third parties.

IDT's products are not intended for use in applications involving extreme environmental conditions or in life support systems or similar devices where the failure or malfunction of an IDT product can be reasonably expected to significantly affect the health or safety of users. Anyone using an IDT product in such a manner does so at their own risk, absent an express, written agreement by IDT.

Integrated Device Technology, IDT and the IDT logo are registered trademarks of IDT. Product specification subject to change without notice. Other trademarks and service marks used herein, including protected names, logos and designs, are the property of IDT or their respective third party owners.

Copyright ©2015 Integrated Device Technology, Inc.. All rights reserved.